

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No.	: 10/622,933	Confirmation No: 3481
Applicant	: Chee Hong Liao	
Filed	: July 18, 2003	
Title	: Method of Processing Test Patterns for an Integrated Circuit	
Art Unit	: 2128	
Examiner	: Saif A. Alhija	
Docket No.	: M&N-IT-465	
Customer No.	: 24131	

**AMENDMENT**

Hon. Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Responsive to the Office action dated October 3, 2006 kindly amend the above-identified application as follows:

- **Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.
- **Remarks/Arguments** begin on page 9 of this paper.